



# Advanced Microwave Systems and Techniques for Non-Metallic Piping

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Bob Stakenborghs

CEO-Advanced Microwave Imaging



# Advanced Microwave Imaging

(AMWI)

Founded 2020

**Bob Stakenborghs, CEO**

16 years experience in field MW inspection and material interaction

ASME, ASTM, ISO, ASNT committee member

Authored ASME, ASTM MW inspection standards

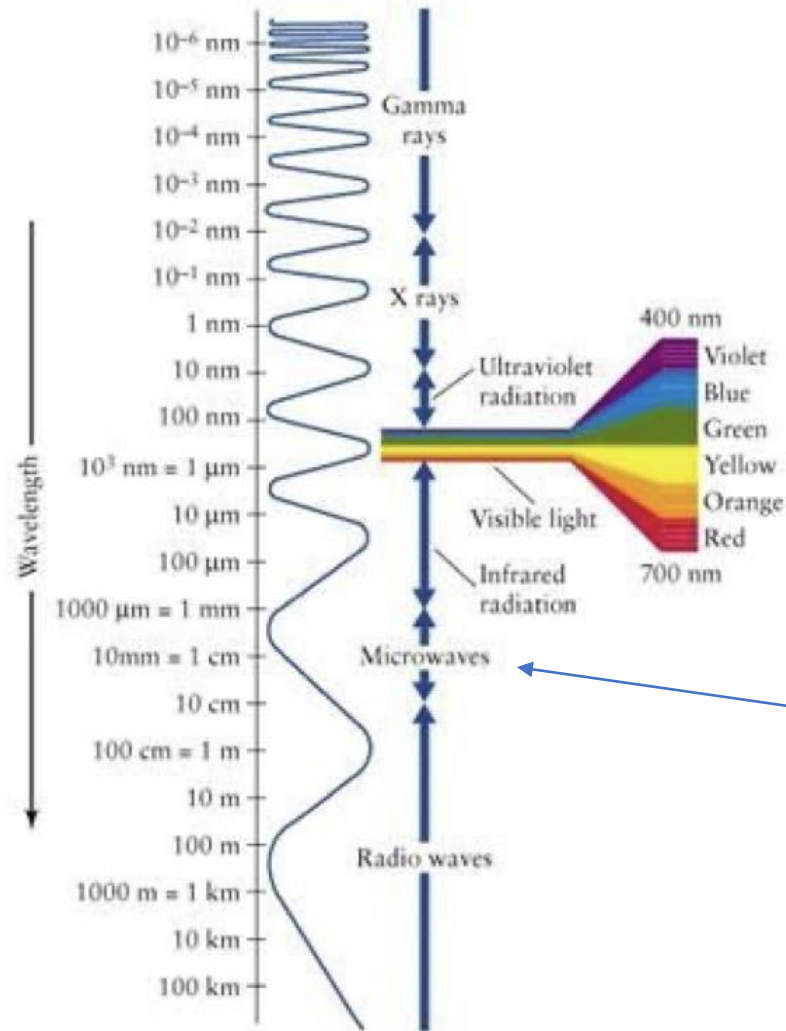
- To advance the art and science of microwave inspection through:
  - State of the art electronics
    - Multi-frequency and advanced single frequency systems
  - Calibrate-able and repeatable systems
    - Simple calibration for repeatable results
  - Bespoke Antenna System
    - Only system with inspection specific antenna
  - Proprietary and specialized data acquisition and analysis software



# Microwave Inspection

Inspection of non-metallic materials using Electro-Magnetic Radiation (EMR) in the microwave frequency range.

Approximately  
300MHz to 300 GHz



MW Frequency Range



# Brief History MW Inspection

- MW Inspection has been described in texts since 1950's
- Field inspection since early 2000's
- Current standards:
  - ASNT - SNT-TC-1A 2016 Microwave Included as a Method
  - ASME BPV Section III Appendix XXVI - MW included as an inspection technique for HDPE piping
  - ASTM E3101 and E3102 - MW Inspection of HDPE butt and Electro Fusion Joints
  - ISO, ASME Section V and other standards under development



# Advanced System

System Characteristics make advanced inspection possible.

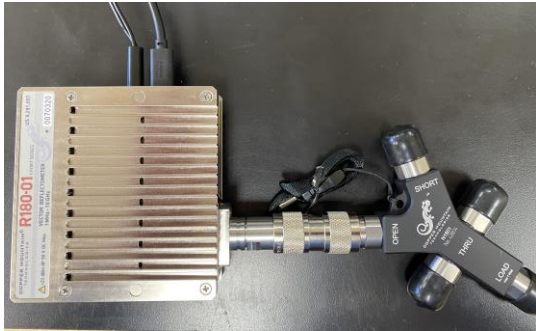
Multi frequency applications using Vector Network Analyzer (VNA) provides additional data for analysis.

- Multi-frequency system
  - Metrology grade equipment used to generate signal
    - VNA – 85MHz to 18GHz range
    - 201,401,801 data points selectable
    - Fully calibrate-able
      - Open
      - Short
      - Load
      - Calibration screen built into data acquisition software
  - Highly repeatable results



# Simple Three Step Calibration

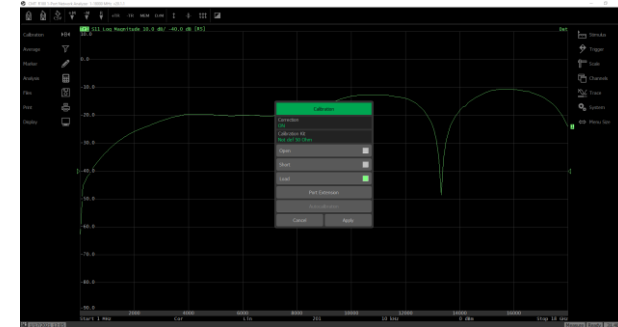
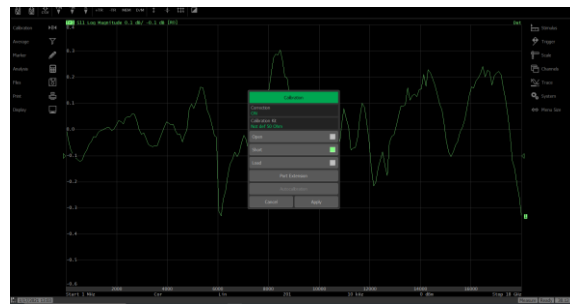
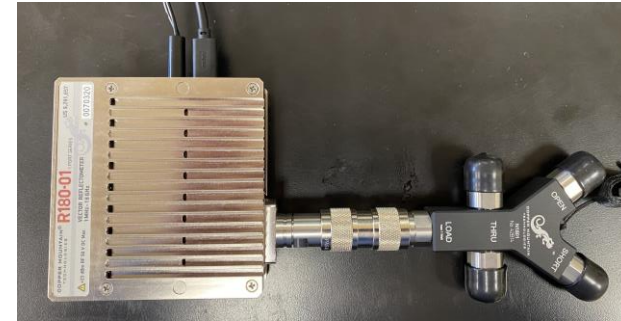
OPEN



SHORT



LOAD



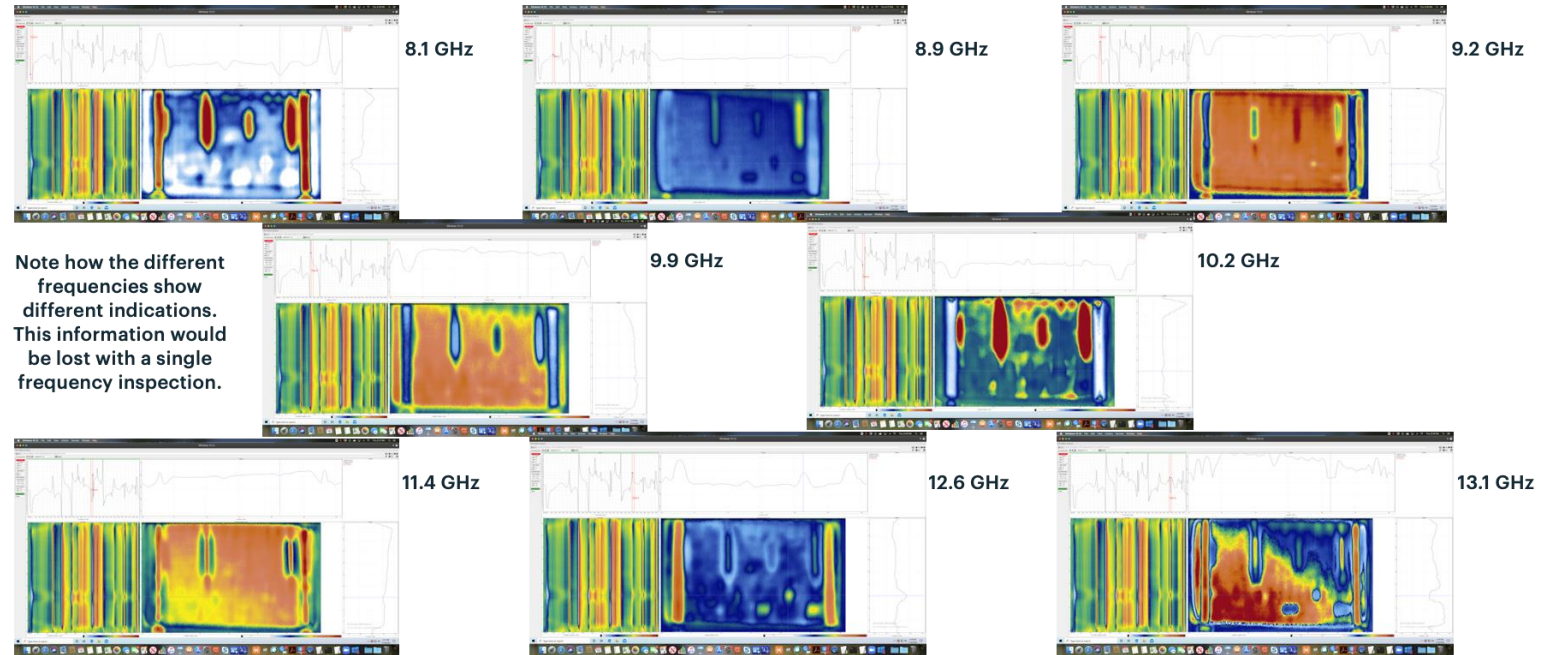
# Advantages of Multi Frequency Interrogation

Data acquisition across a frequency range provides for a large amount of data that can be analyzed

Software allows for display of:

- Real
- Imaginary
- Magnitude
- Phase

## Image Sequence of 25MM Thick Fiberglass Part



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# Bespoke Antenna System

- Only field inspection system using antenna designed specifically for inspection
  - Others use open waveguide which have no controlled spot size and are highly inefficient
  - Can be specifically designed for inspection application
- Characteristics
  - Reasonable match across the band,  $|S_{11}| \sim -10\text{dB}$  or better
  - Field confined to a controlled and well defined spot size
  - To achieve this smaller spot size the mode has been changed by the probe from an air filled waveguide at TE<sub>10</sub> to a rod probe with hybrid HE<sub>11</sub> mode



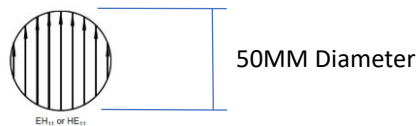


# Antenna Patterns

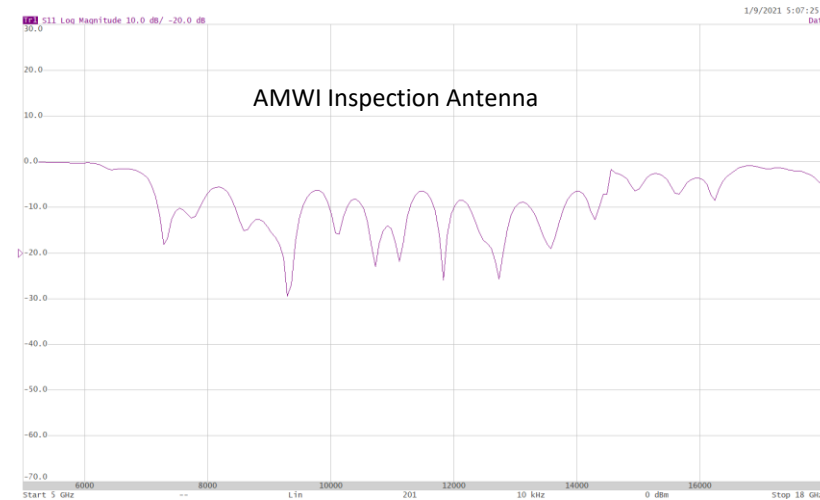
AMWI inspection antenna has multiple return peaks at 20dB or higher plus well defined spot size.

Open waveguide has limited return peaks and not suitable for multi frequency use.

## AMWI Inspection Antenna

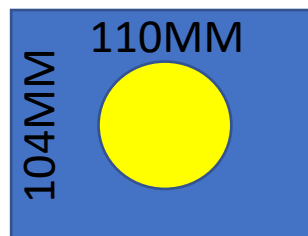


Beam pattern well defined to a spot size of 50MM diameter at 50MM below antenna. (Beam approximately 20MM Diameter at surface)

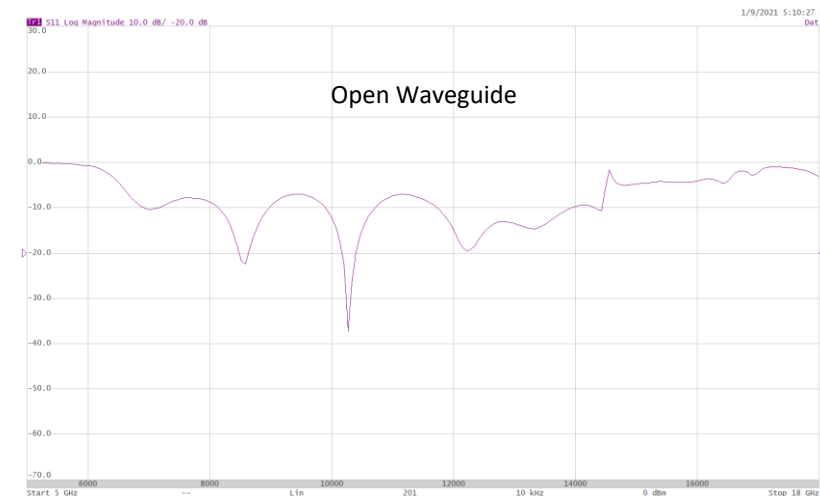


## Open Waveguide

Energy spreads at 45 degrees from aperture in two dimensions plus uncontrolled surface wave and large standing wave ratio at surface



WR42 (24.5 GHz) Open Waveguide  
"Spot" Size at 50MM (Blue)  
versus  
AMWI Antenna at 50MM  
(Yellow)  
(To Scale - Approx.)



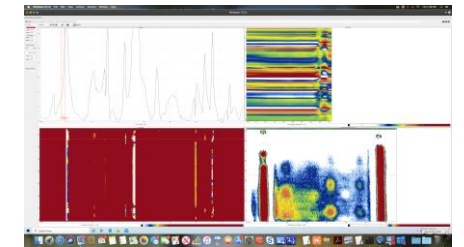
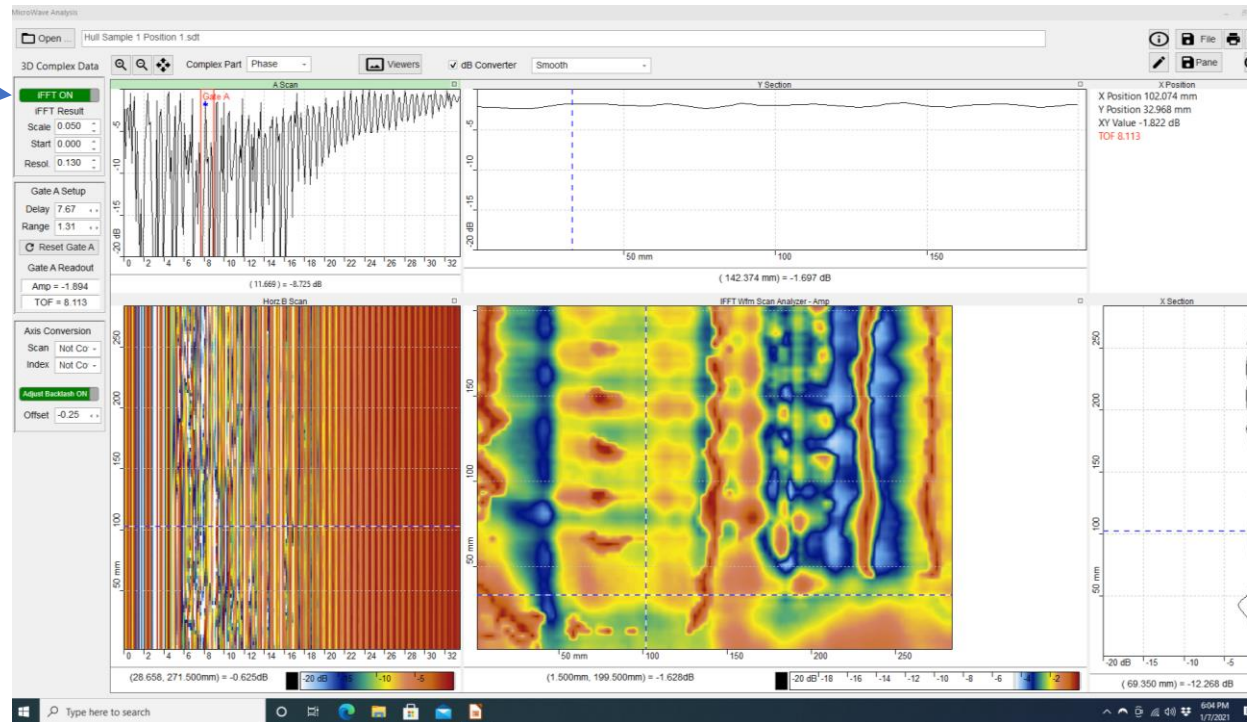
# Specialized Analysis Software

Frequency Sweep allows for IFFT conversion to time/depth domain and easy conversion from frequency to depth

Horizontal "B" (Depth) Scan View

"A" Scan View

"Y" Section view



Alternate "B" Horiz and "B" Vertical views

"X" Section View

"C" Scan View



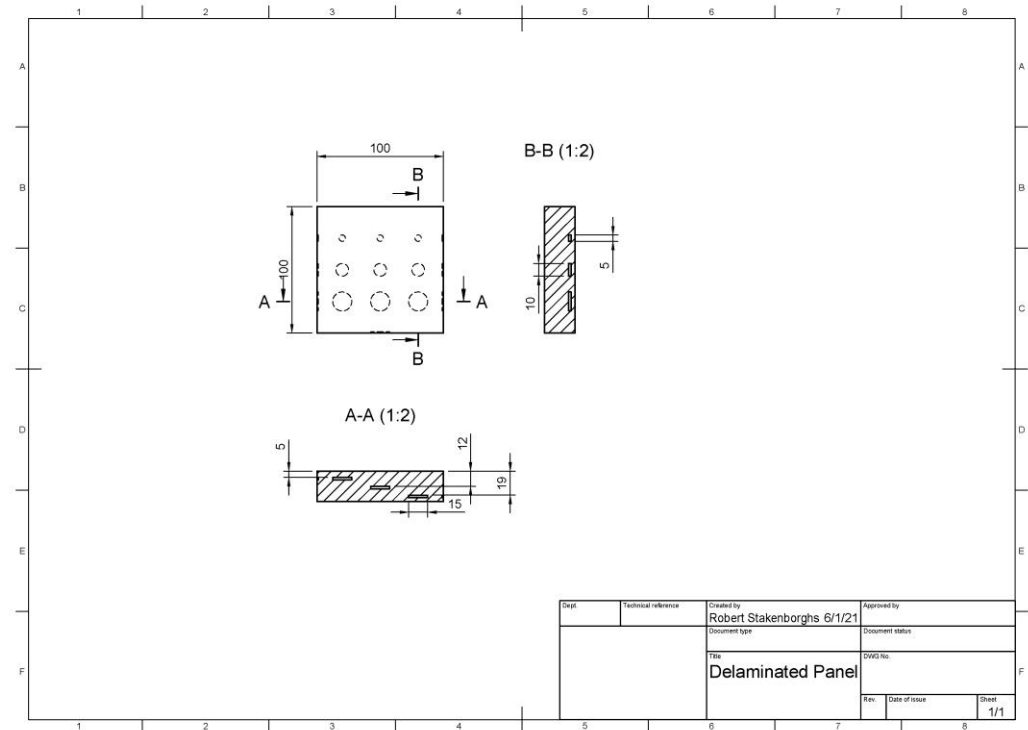
# Sample Creation

Creating flaws in composite structures can be problematic

Delamination flaws can be problematic because of uncertainty associated with maintaining clearance between layers (i.e. - layer contamination)

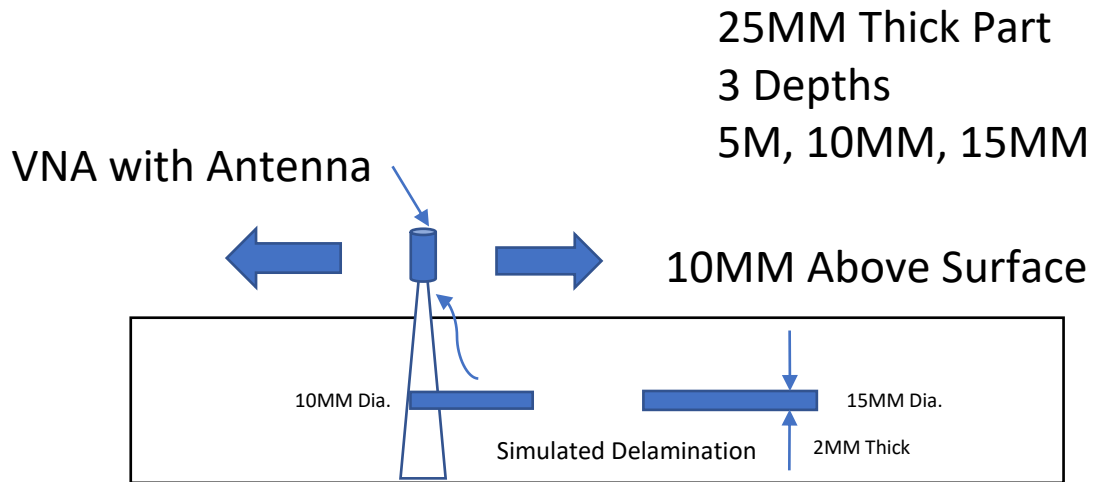
- One possible solution is to design a part with a known delamination and then 3D print that part.
- 3D printing with fiberglass and other materials are now possible.

Example in PLA



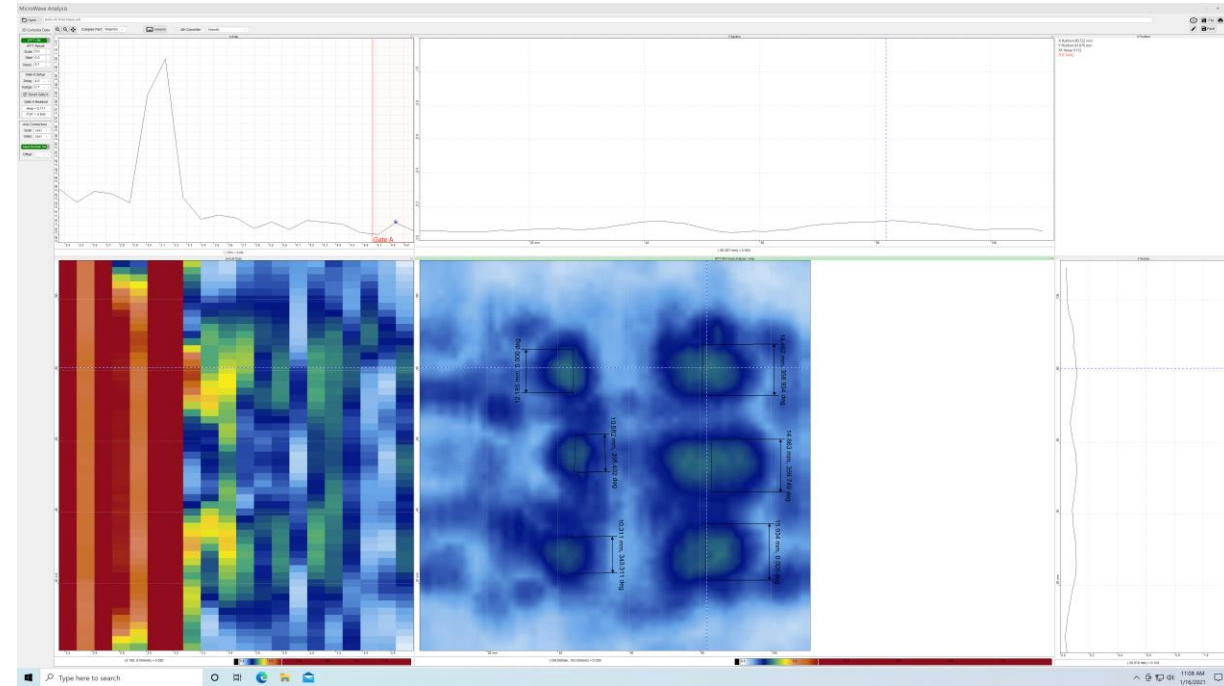
# MW Inspection Advanced System

- Inspection Example (3d Print PLA)



Reflected signal ( $S_{11}$ ) varies based on complex permittivity beneath antenna

Smallest flaws were not detected and likely were not printed properly.



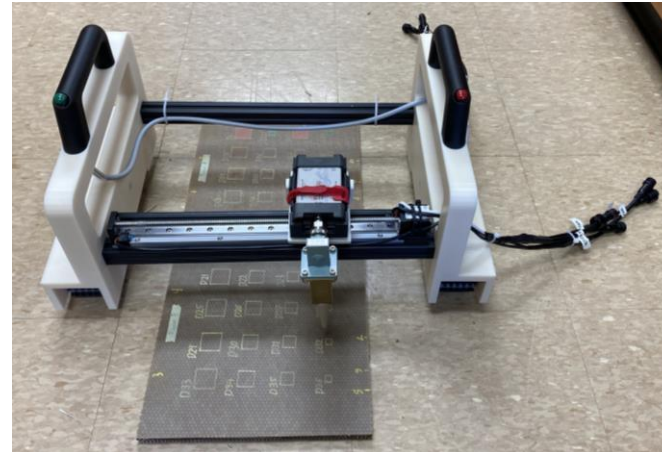
# AMWI Field Inspection Equipment

Pipe Scanner  
(Motorized/manual)



- Motorized Scan Axis
- Manual Index
- Capable of scanning up to 1,000MM Diameter
- Push Button Operation

Motorized Axis Portable  
Scanner (MAPS)



- Motorized scan axis  
(Three different lengths 450MM, 300MM, 200MM)
- Manual Index
- Push Button Operation (Allows hands on scanner)
- Built for Up-Tower Wind Turbine Blade Inspection or Large Pipe

AMWI scanning systems use simple to use data acquisition software that is fully compatible with VNA



# Complex Data Analysis

The availability of complex data, that is complex reflection coefficient  $S_{11}$  made up of dielectric and loss components allows for further analysis

The availability of sophisticated data allows for analysis for evaluation of located flaws in ways that have not been previously been available for microwave inspection.

## Multi-Frequency Data

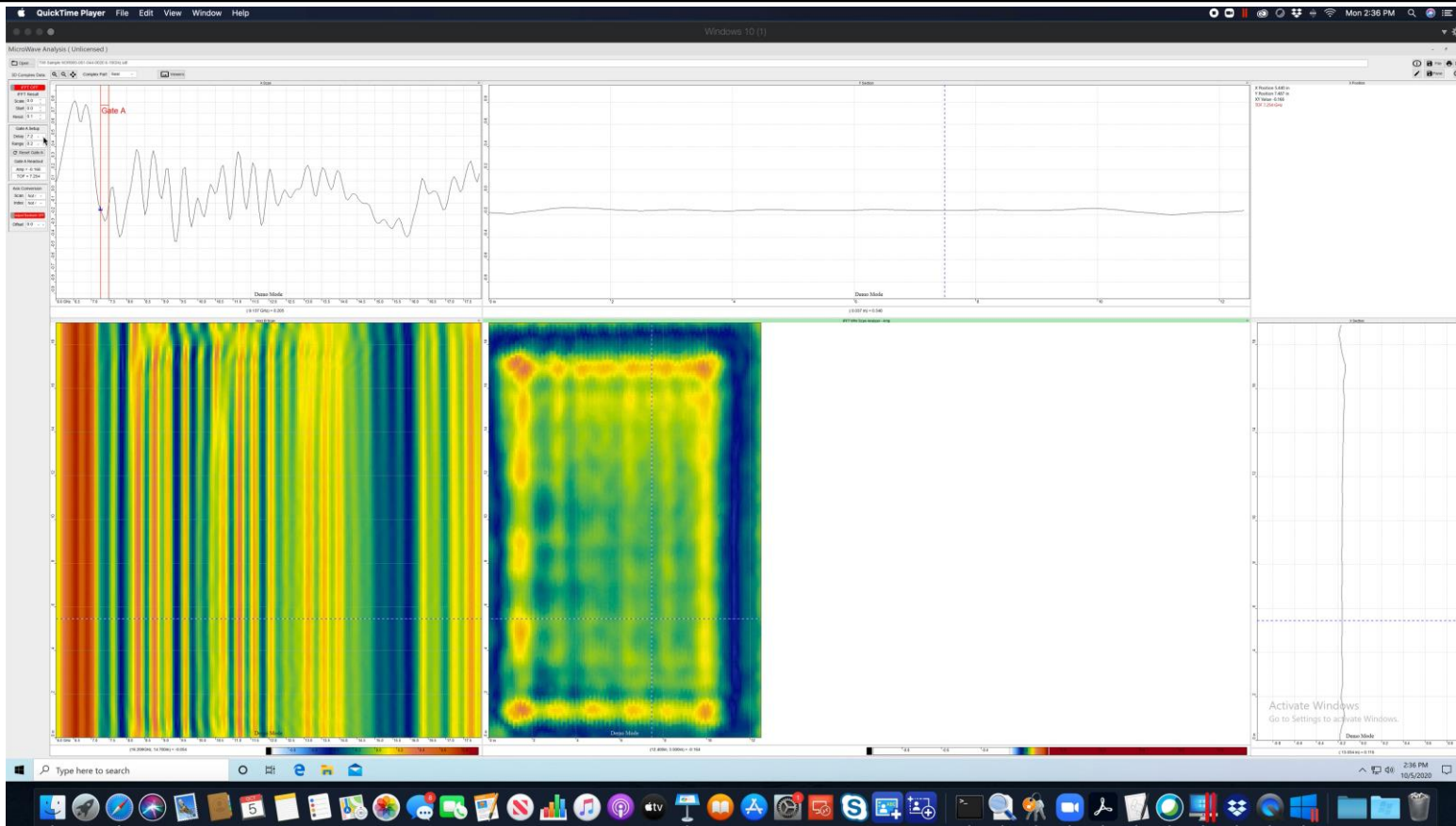
- Allows for viewing of inspection at various frequencies versus only a single frequency
- Different frequencies interact with material slightly differently providing additional information
- Allows for conversion of frequency based data to time based data using IFFT
- Provides for selection of a best single frequency for SAFT

## Complex Reflection Coefficient

- Allows for viewing real and imaginary data as well as calculating true magnitude and phase
- True phase provides a tremendous amount of information about the MUT
- Allows for SAFT analysis

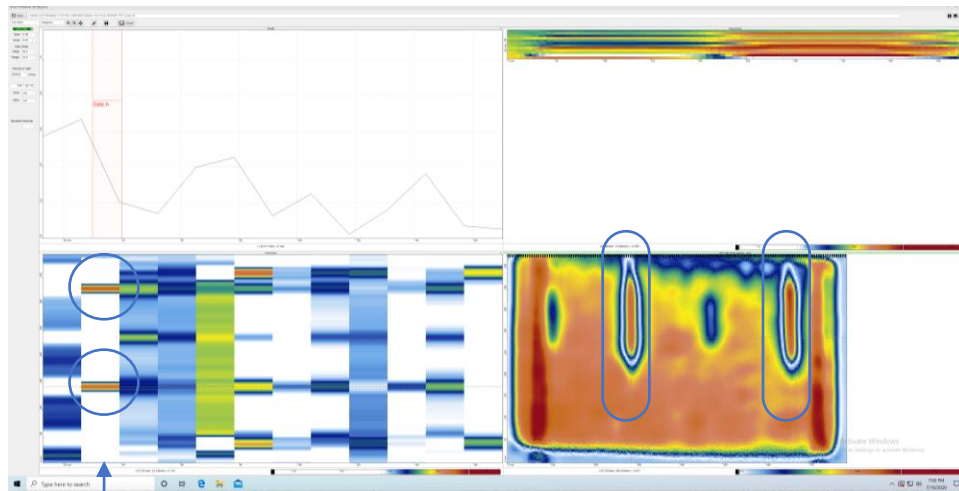


# Frequency Variance

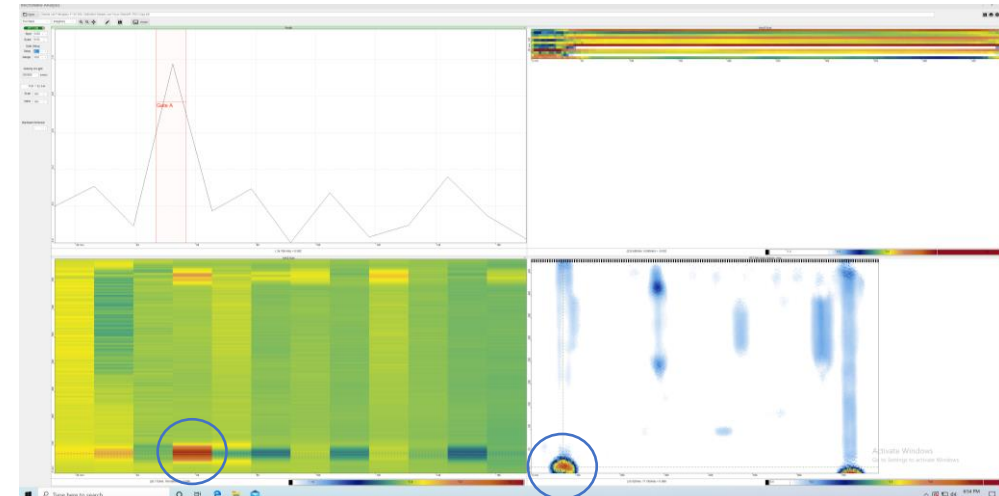


Fiberglass panel with  
back drilled holes of  
varying size and  
depth.

# Depth Detection using IFFT



Location Near Side of MUT



Location Far Side of MUT

Depth Capabilities with Proper Calibration  
(25MM Thick Fiberglass Part)



# Synthetic Aperture Focusing

- Developed in laboratory setting for microwave inspection
- Using AMWI equipment, SAFT can be performed with field acquired data
- Allows for better resolution of depth than IFFT alone

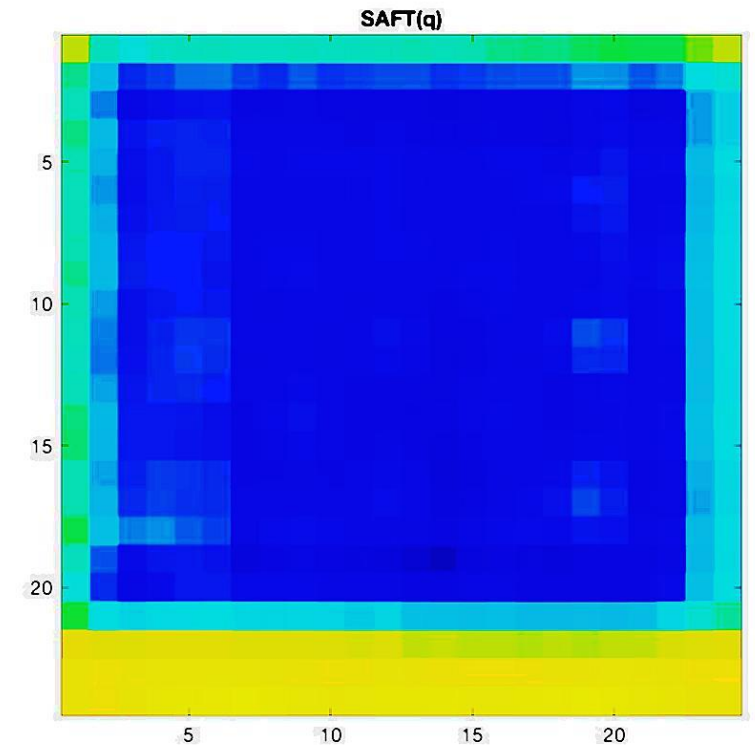
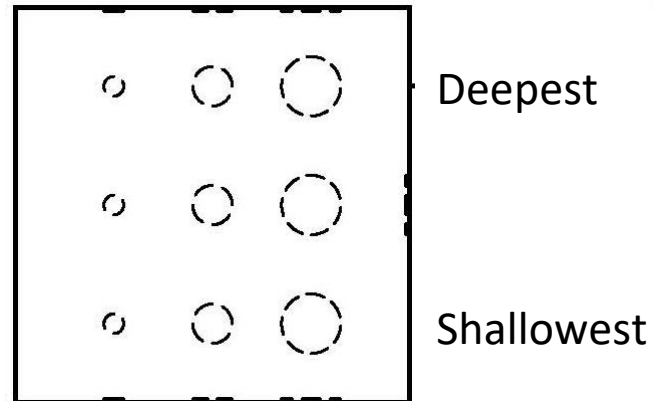
# SAFT EXAMPLE

3D Print PLA Sample

Delamination flaws at various depths in part

Each image represents approximately 1MM of depth below the antenna

The defects begin to appear at approximately (-) 5MM and persist until approximately (-) 12MM. The deepest (Top defects) appear later in the images.



# HDPE Butt Fusion Pipe Inspection



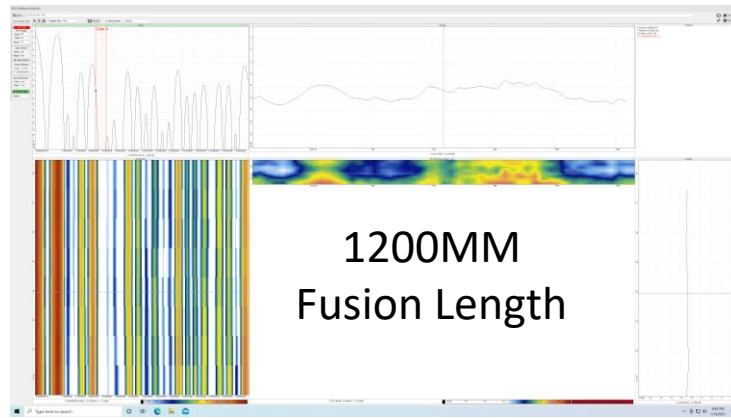
# HDPE Pipe Inspection 6GHz to 14GHz

Pipe 14" SDR 11 PE4710

Multiple fusions of various  
quality

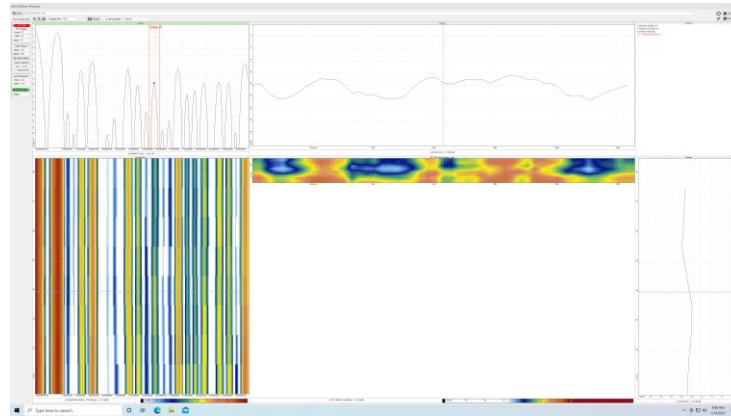
Each frequency provides  
sights different information

Frequency or image selection  
based on pre-determined  
accept/reject criteria selection

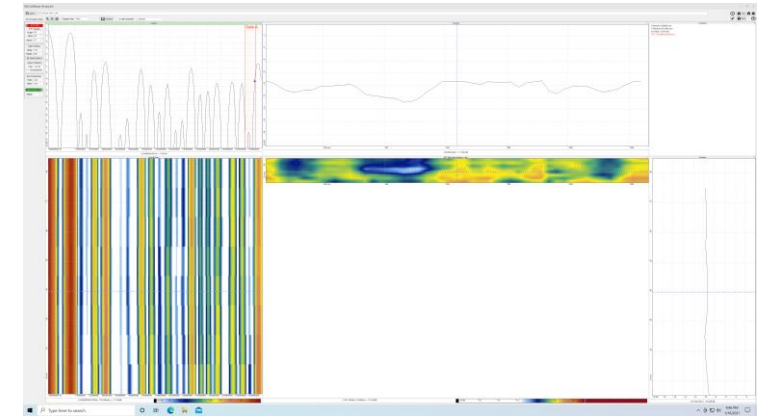


80 MM (40MM Each Side of Fusion)

Frequency 1 - 8.25GHz



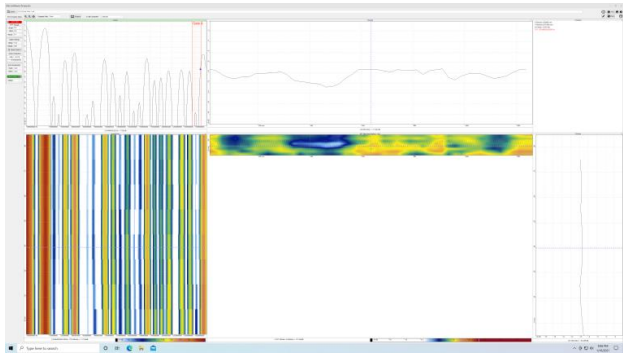
Frequency 2 - 10.25GHz



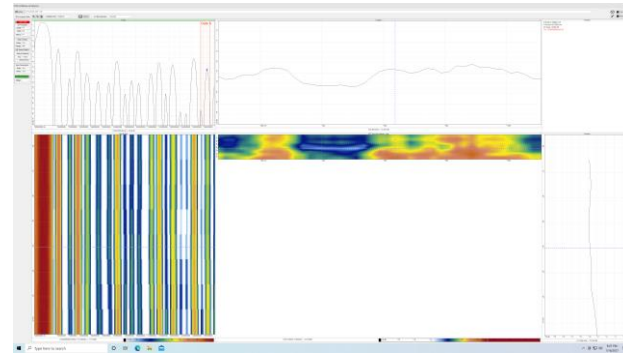
Frequency 2 - 13.25GHz

# HDPE Inspection Accept/Reject

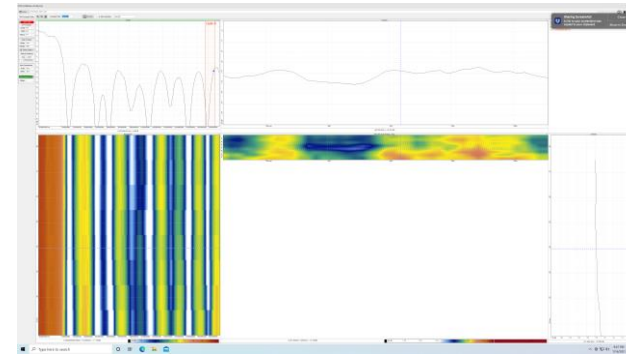
- Different Signal ( $S_{11}$ ) Parts Displayed at Same Frequency



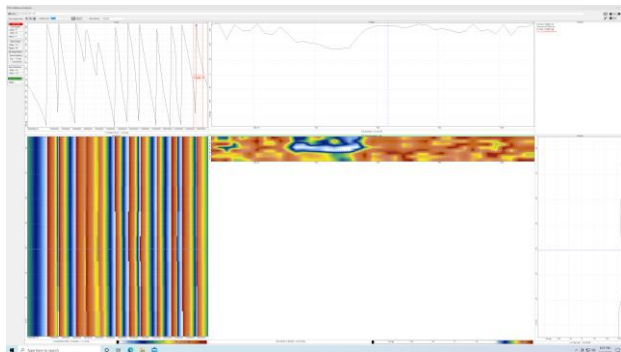
Real



Imaginary



Magnitude



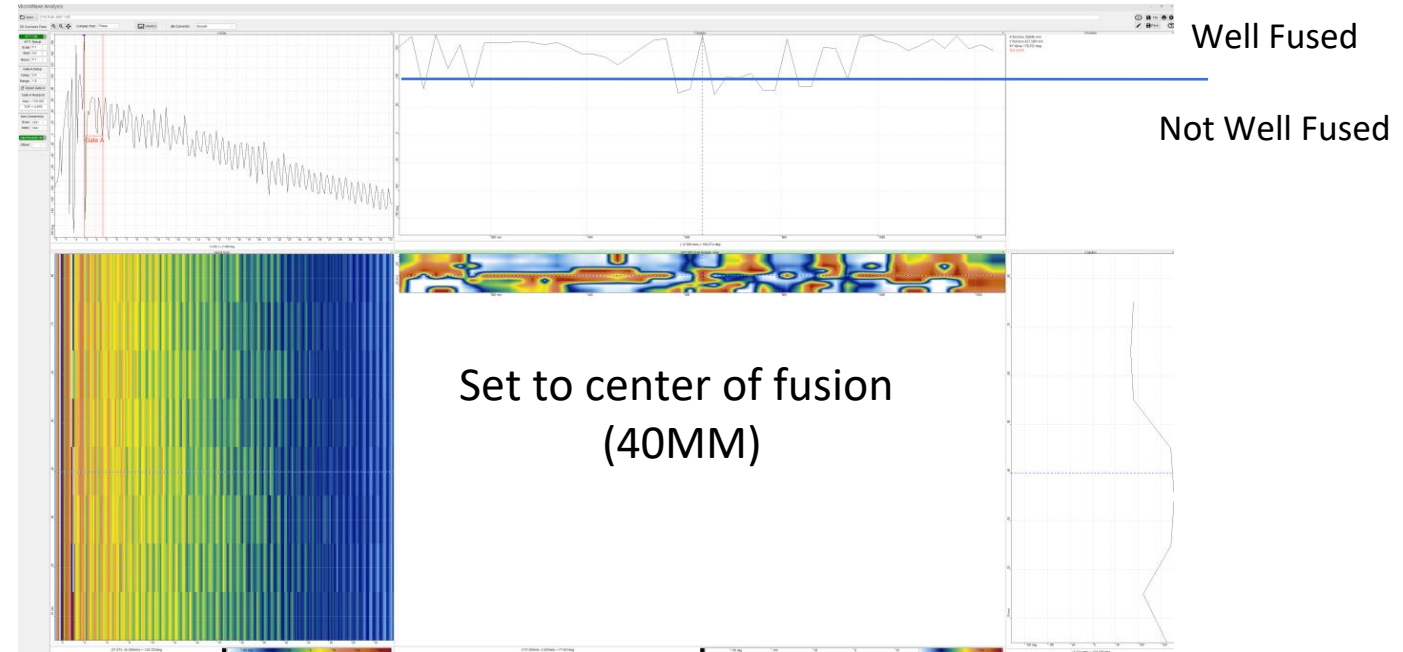
Phase

# HDPE Accept Reject

Final selection based on  
mechanical testing of test  
fusions

Currently, IFFT of PHASE  
signal seems to provide  
excellent sensitivity and  
repeatability of signal

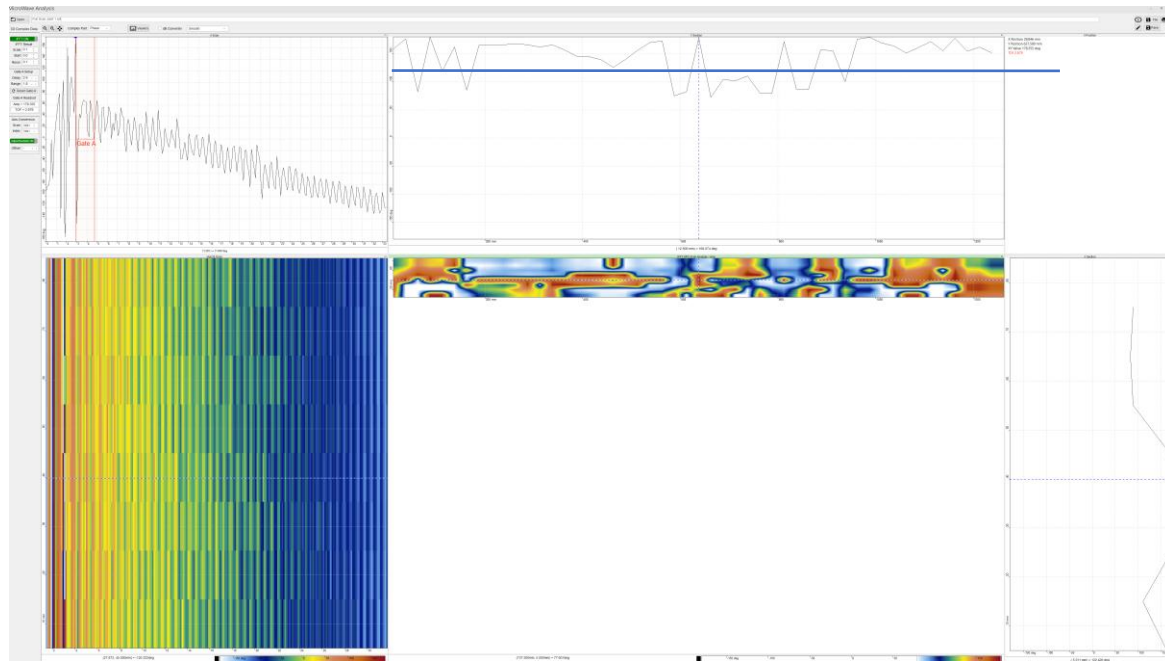
## IFFT of Phase



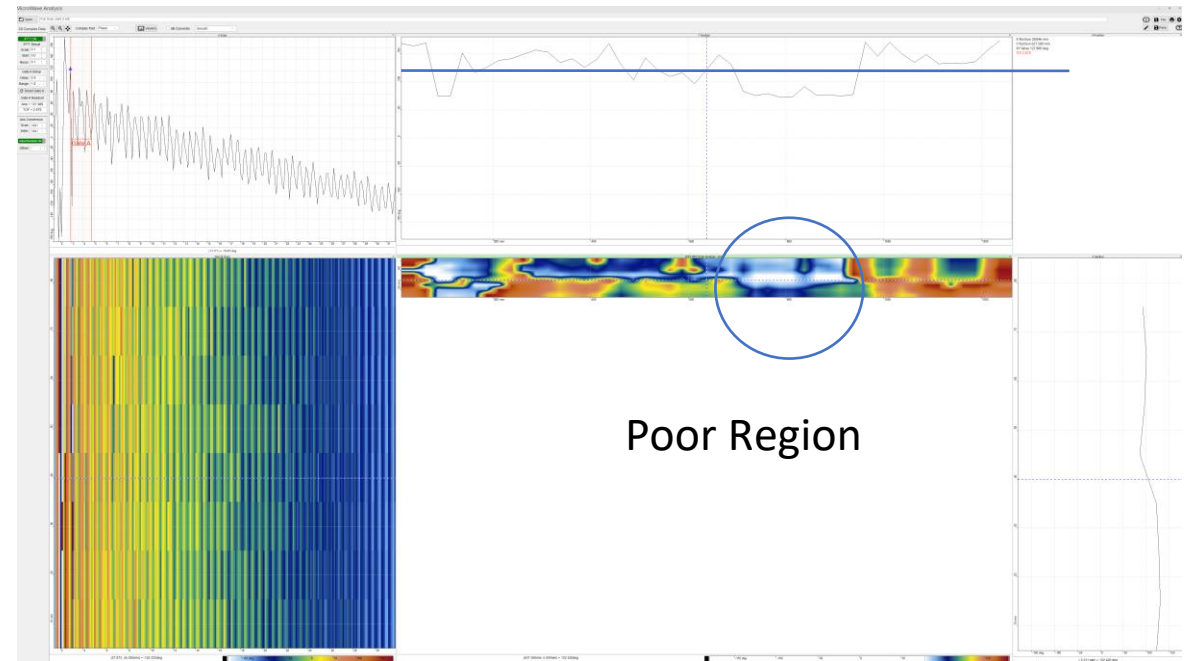
Procedure (Preliminary based on small sample set)

- Set image to IFFT of Phase
- Set "X" Section to 40 MM (Fusion Center)
- Set Accept/Reject to 100 Degrees Phase
- Above - Acceptable
- Below - Reject

# Sample Set Fusions 1 and 2



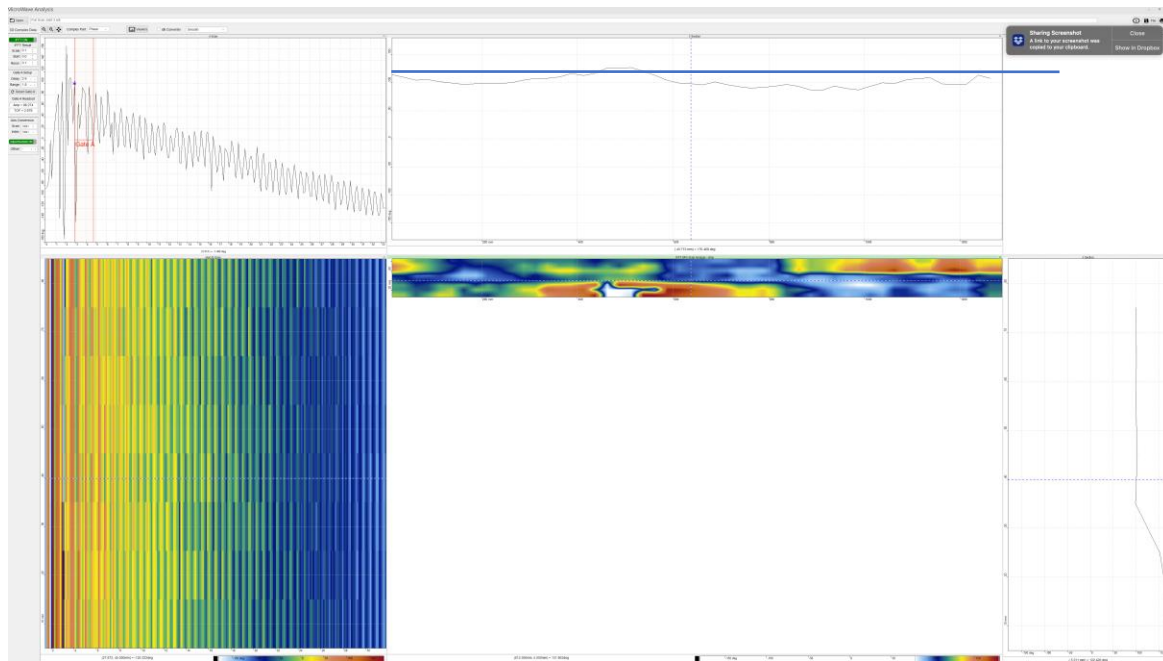
PASS



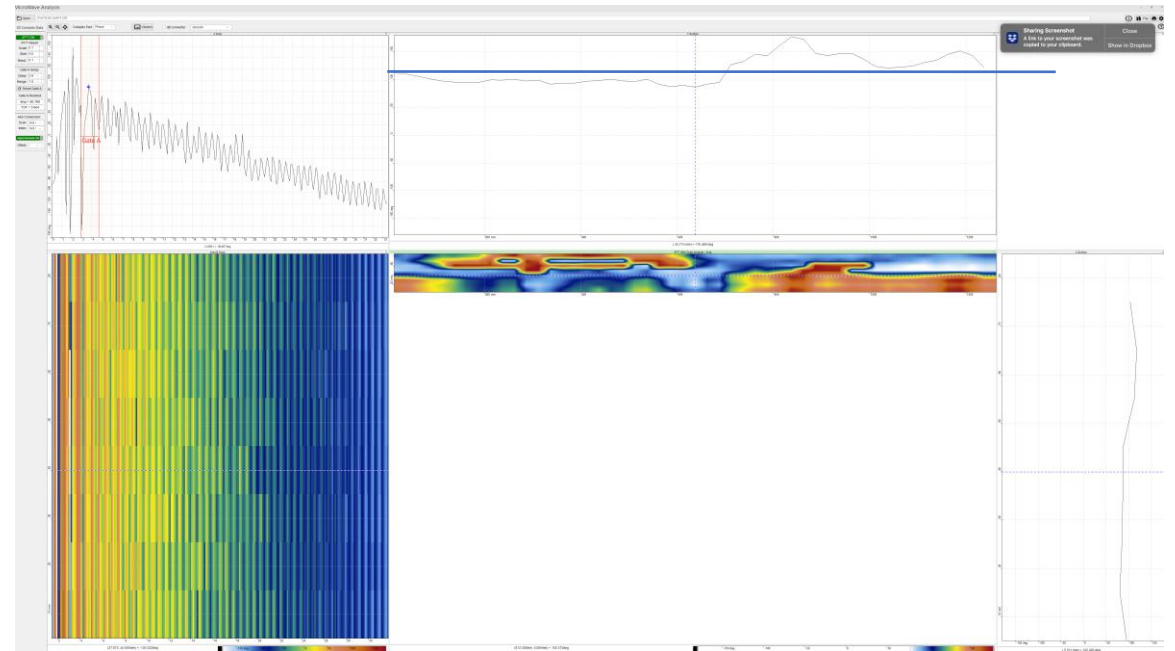
Poor Region

REJECT

# Sample Set Fusions 3 and 4



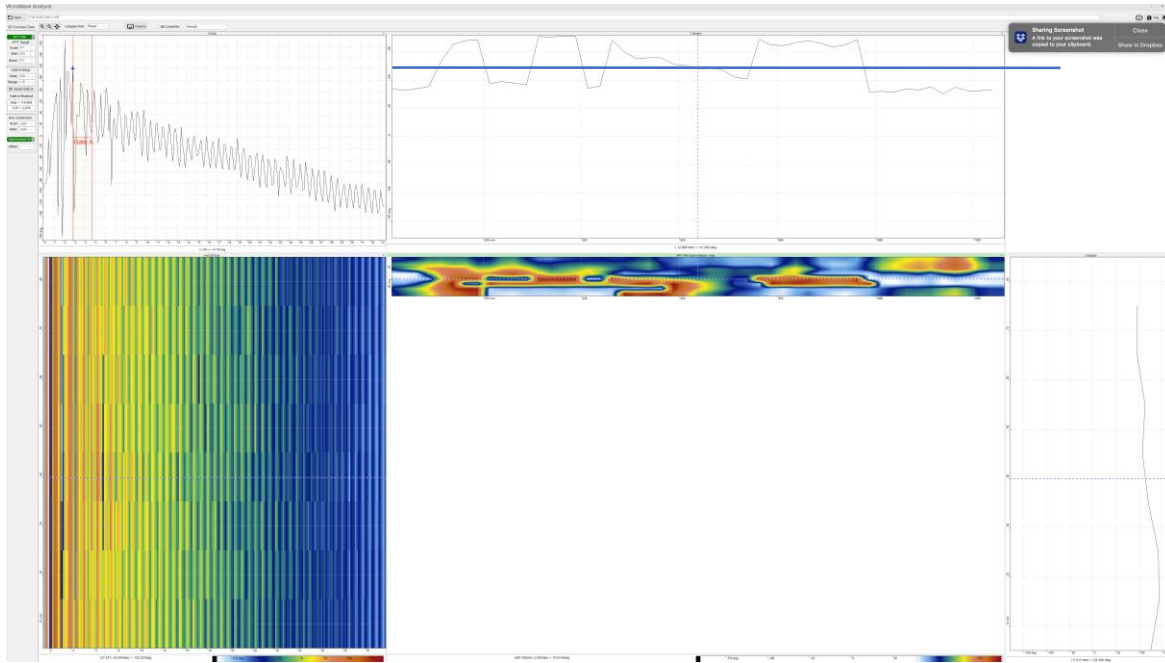
REJECT



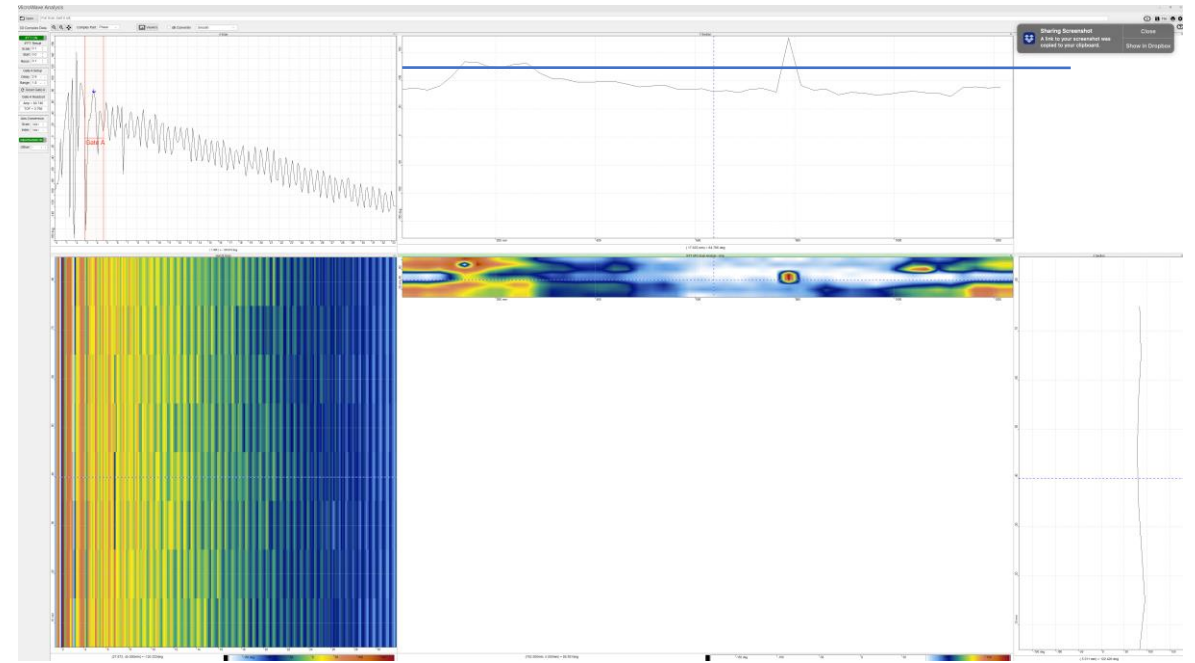
REJECT



# Sample Set Fusions 5 and 6



PASS



REJECT



# FUTURE PLANS

AMWI is advancing the technology of microwave inspection for all applications.

ADVANCED MICROWAVE  
IMAGING

THE FUTURE OF MICROWAVE  
INSPECTION

## Active Programs in AMWI

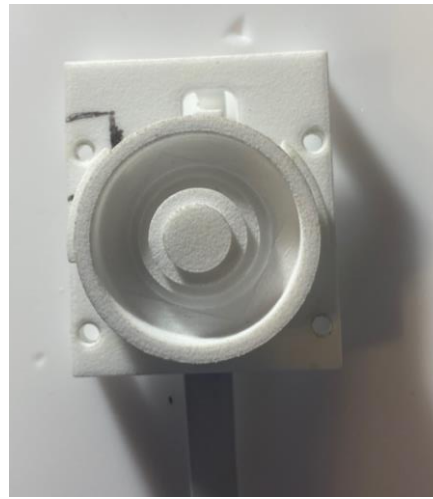
- Improve spatial and depth resolution using advanced analytical algorithms
  - MUSIC (**M**ultiple **S**ignal **C**lassification)
  - 3D Hologram of Part using SAFT as a stepping stone
- Produce new scanning platforms to enhance areas of usefulness
  - Microwave Inspection of Carbon Fiber
  - Hand held thickness gun (HDPE and Fiberglass)
  - Fully motorized pipe scanner
- Take advantage of new sensor packages
  - Direct Time of Flight Sensor Package
  - ID Inspection pipe PIG using TOF device
  - Lightweight 3-D printed antenna parts for drone mounted volumetric inspection equipment



# Time of Flight Microwave

Time of flight sensor is the one  
of the latest developments in  
MW inspection

Allows for true TOF detection  
capability

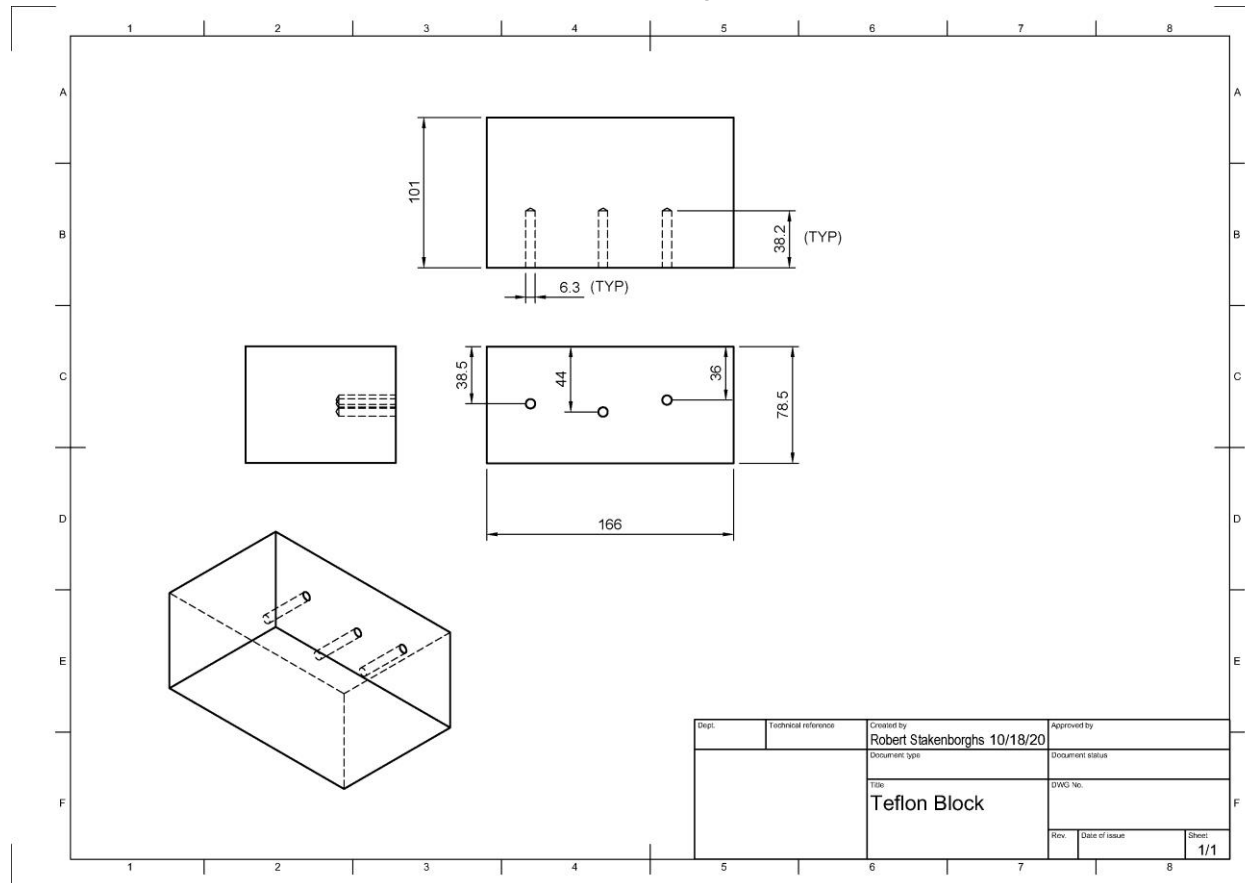


- Similar to UT Time Based Inspection
  - Microwave signal pulse generated at transmit antenna
  - Return reflected signal measured at receive antenna
  - Receive signal coherent with transmit signal
  - Time measured in Pico Seconds ( $10^{-12}$  Seconds)
- Speed of light  $3^8$  Meters per Second
- Distance resolution on the order of 0.3 MM (possible, depends on signal amplitude)



# T0F Example

## Teflon Block (Dielectric Constant = 2.1)



### Depth Info

Back Wall = 78.5MM

Flaw 1 = 38.5 MM

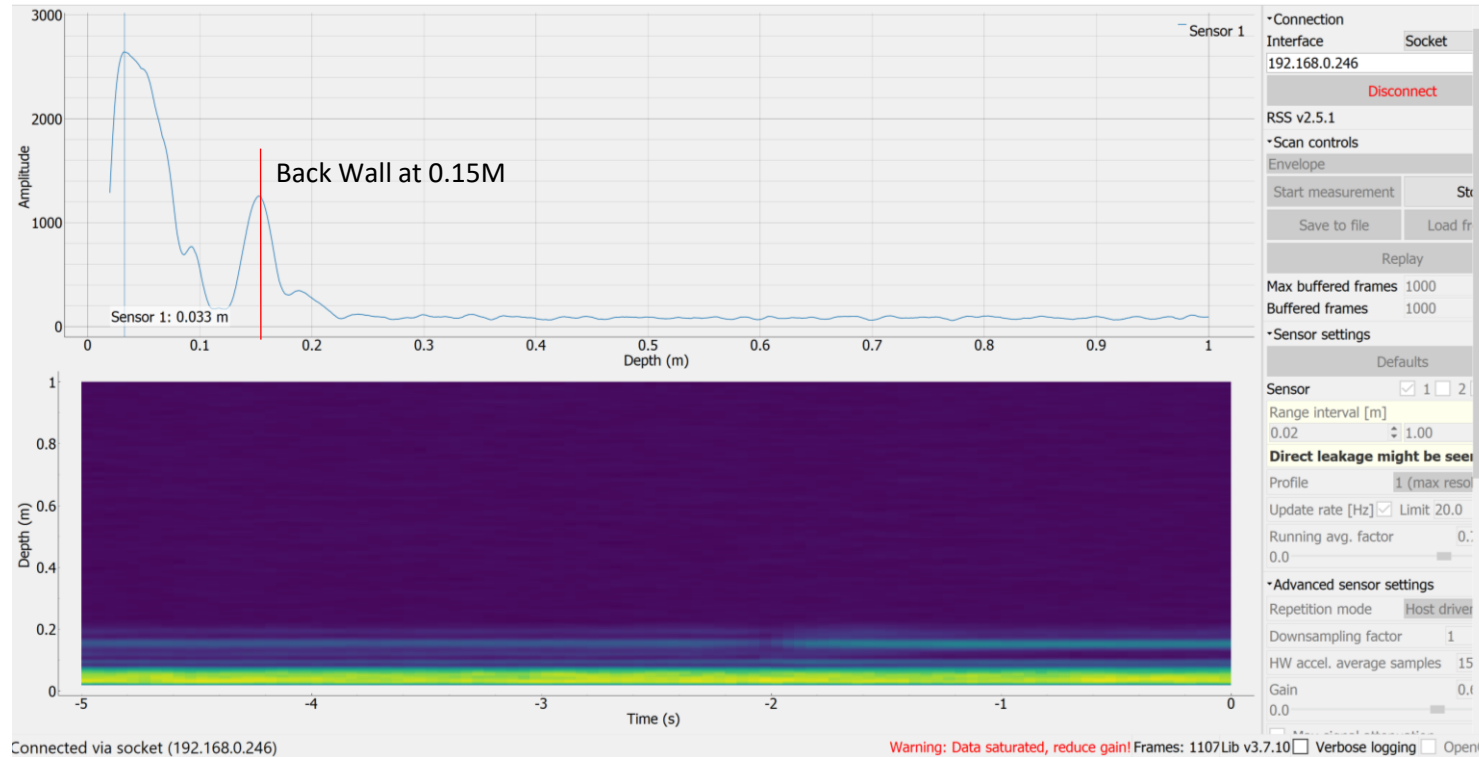
Flaw 2 = 44MM

Flaw 3 = 36MM



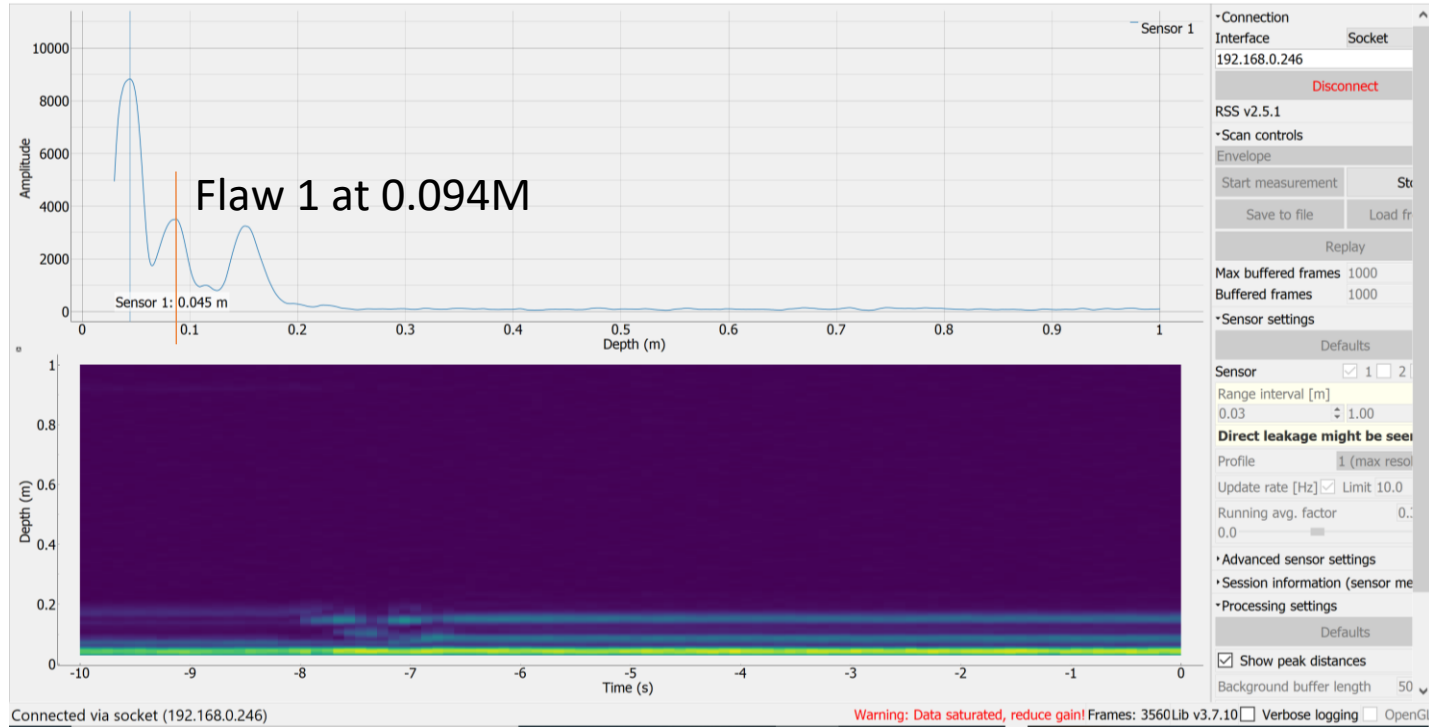
# Back Wall Reflection Actual Depth = 78.5MM

Depth equals reflected signal (0.15M) minus front wall (0.033M) divided by square root of dielectric constant (1.45) equals 80.7MM



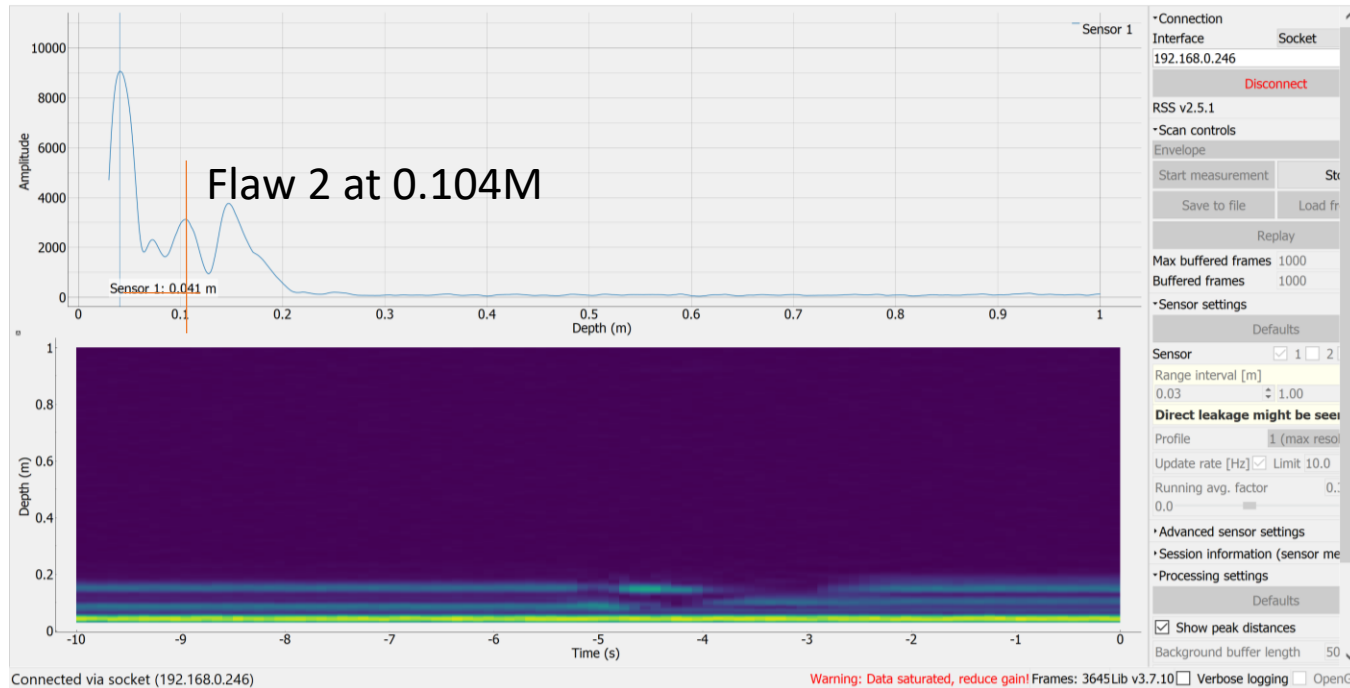
# Flaw 1 (Left Hole) Actual Depth = 38.5MM

Measured Depth =  
 $(0.094M - 0.045M)/1.45$   
= 33.7MM



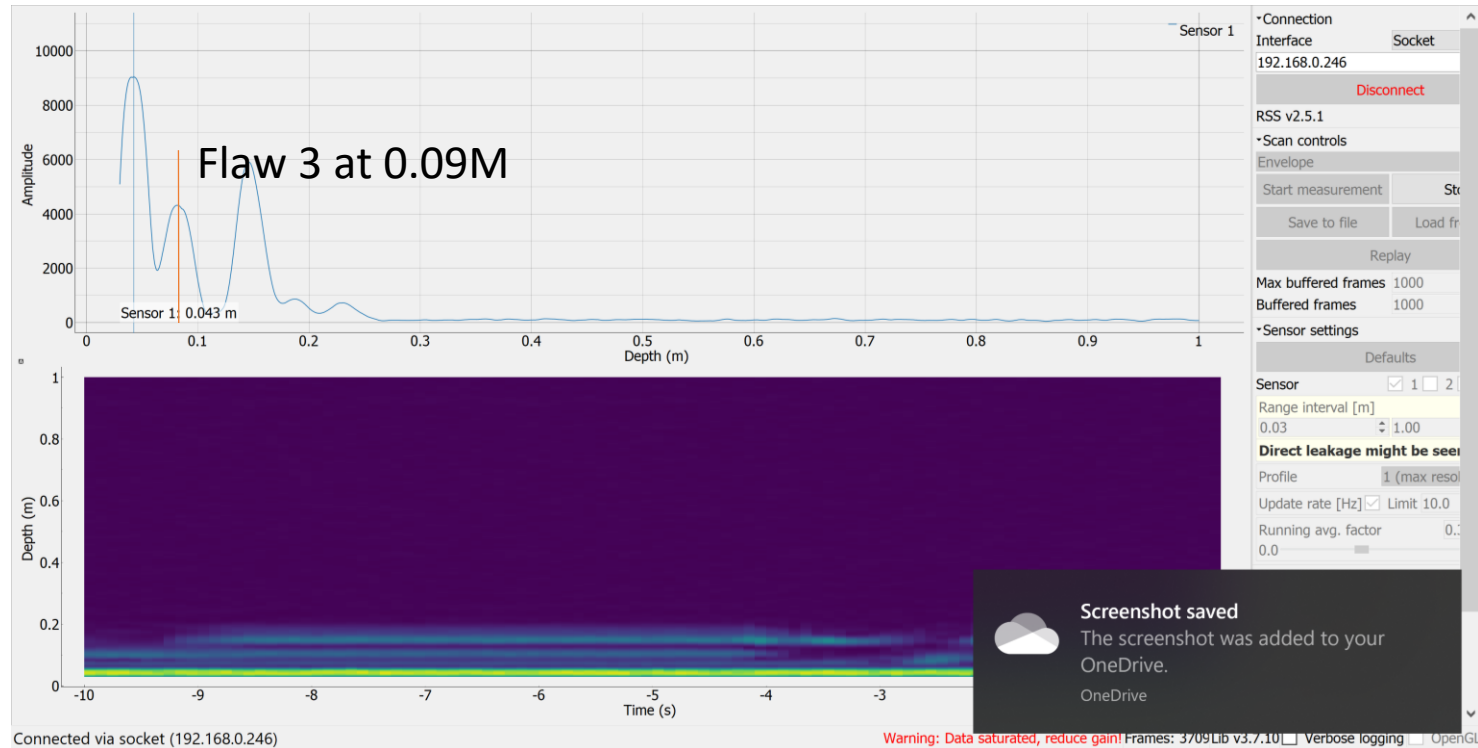
# Flaw 2 Actual Depth = 44MM

Measured Depth =  
 $(0.104\text{M} - 0.041\text{M})/1.45$   
= 45MM



# Flaw 3 (Right Hole) Actual Depth = 36MM

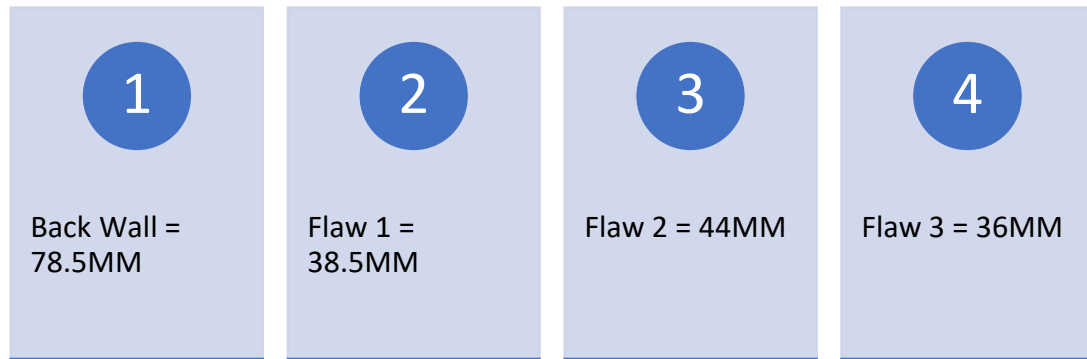
Measured Depth =  
 $(0.09\text{M} - 0.043\text{M})/1.45$   
= 32.4MM



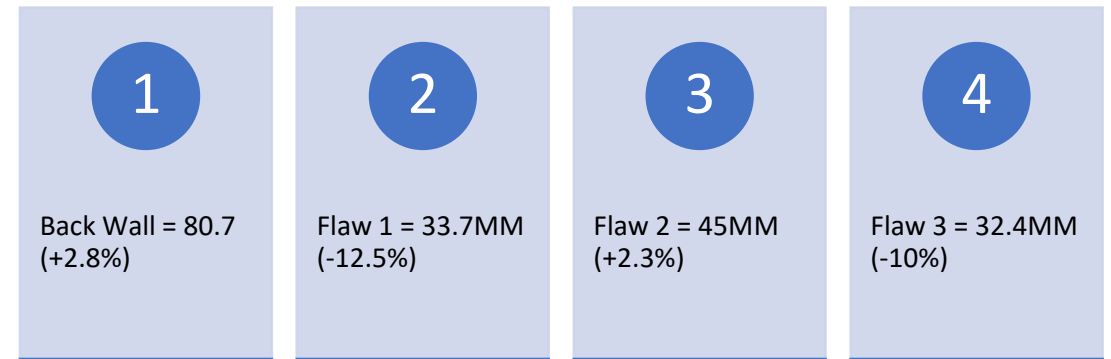


# Comparison of Actual to Time of Flight Measured Flaw

## ACTUAL LOCATION



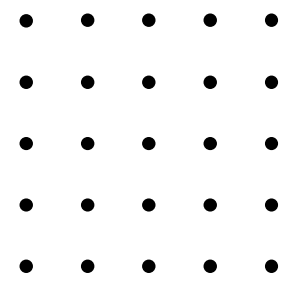
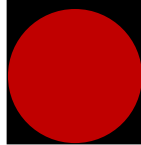
## MEASURED LOCATION





# Q & A

What can we answer for you?



**Advanced Microwave  
Imaging**



Check out our article in September 2020 Advanced Materials and Processes



<https://static.asminternational.org/amp/202006/16/>



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# Contact Us

Advanced Microwave Imaging

Bob Stakenborghs

[rjstak@advancedmwimaging.com](mailto:rjstak@advancedmwimaging.com)

+001(225) 329-5815

[www.advancedmwimaging.com](http://www.advancedmwimaging.com)